

Notice of References Cited

 Application/Control No.
 10/674,292

 Applicant(s)/Patent Under
 Reexamination
 HASEI ET AL.

 Examiner
 Yewebdar T Tadesse

 Art Unit
 1734

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2003/0137242	07-2003	Seki, Shunichi	313/506
B	US-2003/0008217	01-2003	Kobayashi, Hironori	430/5
C	US-2003/0059686	03-2003	Kobayashi et al.	430/5
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.